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Details

Product Status	Obsolete
Core Processor	508
Core Size	8-Bit
Speed	40MHz
Connectivity	I ² C, LINbus, SCI, SPI
Peripherals	LVD, POR, PWM, WDT
Number of I/O	25
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	1.5K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 10x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	32-LQFP
Supplier Device Package	32-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/s9s08dn32f1mlc

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The IRQ pin, when enabled, defaults to use an internal pull device (IRQPDD = 0), the device is a pull-up or pull-down depending on the polarity chosen. If the user desires to use an external pull-up or pull-down, the IRQPDD can be written to a 1 to turn off the internal device.

BIH and BIL instructions may be used to detect the level on the IRQ pin when the pin is configured to act as the IRQ input.

5.5.2.2 Edge and Level Sensitivity

The IRQMOD control bit reconfigures the detection logic so it detects edge events and pin levels. In the edge and level detection mode, the IRQF status flag becomes set when an edge is detected (when the IRQ pin changes from the deasserted to the asserted level), but the flag is continuously set (and cannot be cleared) as long as the IRQ pin remains at the asserted level.

5.5.3 Interrupt Vectors, Sources, and Local Masks

Table 5-1 provides a summary of all interrupt sources. Higher-priority sources are located toward the bottom of the table. The high-order byte of the address for the interrupt service routine is located at the first address in the vector address column, and the low-order byte of the address for the interrupt service routine is located at the next higher address.

When an interrupt condition occurs, an associated flag bit becomes set. If the associated local interrupt enable is 1, an interrupt request is sent to the CPU. Within the CPU, if the global interrupt mask (I bit in the CCR) is 0, the CPU will finish the current instruction; stack the PCL, PCH, X, A, and CCR CPU registers; set the I bit; and then fetch the interrupt vector for the highest priority pending interrupt. Processing then continues in the interrupt service routine.



An output pin can be selected to have high output drive strength by setting the corresponding bit in the drive strength select register (PTxDSn). When high drive is selected, a pin is capable of sourcing and sinking greater current. Even though every I/O pin can be selected as high drive, the user must ensure that the total current source and sink limits for the MCU are not exceeded. Drive strength selection is intended to affect the DC behavior of I/O pins. However, the AC behavior is also affected. High drive allows a pin to drive a greater load with the same switching speed as a low drive enabled pin into a smaller load. Because of this, the EMC emissions may be affected by enabling pins as high drive.

6.3 Pin Interrupts

Port A, port B, and port D pins can be configured as external interrupt inputs and as an external means of waking the MCU from stop or wait low-power modes.



The block diagram for each port interrupt logic is shown Figure 6-2.

Figure 6-2. Port Interrupt Block Diagram

Writing to the PTxPSn bits in the port interrupt pin select register (PTxPS) independently enables or disables each port pin. Each port can be configured as edge sensitive or edge and level sensitive based on the PTxMOD bit in the port interrupt status and control register (PTxSC). Edge sensitivity can be software programmed to be either falling or rising; the level can be either low or high. The polarity of the edge or edge and level sensitivity is selected using the PTxESn bits in the port interrupt edge select register (PTxSC).

Synchronous logic is used to detect edges. Prior to detecting an edge, enabled port inputs must be at the deasserted logic level. A falling edge is detected when an enabled port input signal is seen as a logic 1 (the deasserted level) during one bus cycle and then a logic 0 (the asserted level) during the next cycle. A rising edge is detected when the input signal is seen as a logic 0 during one bus cycle and then a logic 1 during the next cycle.

6.3.1 Edge Only Sensitivity

A valid edge on an enabled port pin will set PTxIF in PTxSC. If PTxIE in PTxSC is set, an interrupt request will be presented to the CPU. Clearing of PTxIF is accomplished by writing a 1 to PTxACK in PTxSC.

6.5.1.3 Port A Pull Enable Register (PTAPE)



Figure 6-5. Internal Pull Enable for Port A Register (PTAPE)

Table 6-3. PTAPE Register Field Descriptions

Field	Description
7:0	Internal Pull Enable for Port A Bits — Each of these control bits determines if the internal pull-up or pull-down
PTAPE[7:0]	device is enabled for the associated PTA pin. For port A pins that are configured as outputs, these bits have no
	effect and the internal pull devices are disabled.
	0 Internal pull-up/pull-down device disabled for port A bit n.
	1 Internal pull-up/pull-down device enabled for port A bit n.

NOTE

Pull-down devices only apply when using pin interrupt functions, when corresponding edge select and pin select functions are configured.

6.5.1.4 Port A Slew Rate Enable Register (PTASE)

	7	6	5	4	3	2	1	0
R W	PTASE7	PTASE6	PTASE5	PTASE4	PTASE3	PTASE2	PTASE1	PTASE0
Reset:	0	0	0	0	0	0	0	0

Figure 6-6. Slew Rate Enable for Port A Register (PTASE)

Table 6-4. PTASE Register Field Descriptions

Field	Description
7:0 PTASE[7:0]	 Output Slew Rate Enable for Port A Bits — Each of these control bits determines if the output slew rate control is enabled for the associated PTA pin. For port A pins that are configured as inputs, these bits have no effect. Output slew rate control disabled for port A bit n. Output slew rate control enabled for port A bit n.

Note: Slew rate reset default values may differ between engineering samples and final production parts. Always initialize slew rate control to the desired value to ensure correct operation.



6.5.1.7 Port A Interrupt Pin Select Register (PTAPS)



Figure 6-9. Port A Interrupt Pin Select Register (PTAPS)

Table 6-7. PTAPS Register Field Descriptions

Field	Description
7:0 PTAPS[7:0]	 Port A Interrupt Pin Selects — Each of the PTAPSn bits enable the corresponding port A interrupt pin. 0 Pin not enabled as interrupt. 1 Pin enabled as interrupt.

6.5.1.8 Port A Interrupt Edge Select Register (PTAES)

_	7	6	5	4	3	2	1	0
R W	PTAES7	PTAES6	PTAES5	PTAES4	PTAES3	PTAES2	PTAES1	PTAES0
Reset:	0	0	0	0	0	0	0	0

Figure 6-10. Port A Edge Select Register (PTAES)

Table 6-8. PTAES Register Field Descriptions

Field	Description
7:0 PTAES[7:0]	 Port A Edge Selects — Each of the PTAESn bits serves a dual purpose by selecting the polarity of the active interrupt edge as well as selecting a pull-up or pull-down device if enabled. 0 A pull-up device is connected to the associated pin and detects falling edge/low level for interrupt generation. 1 A pull-down device is connected to the associated pin and detects rising edge/high level for interrupt generation.



6.5.3.3 Port C Pull Enable Register (PTCPE)



Figure 6-21. Internal Pull Enable for Port C Register (PTCPE)

Table 6-19. PTCPE Register Field Descriptions

Field	Description
7:0	Internal Pull Enable for Port C Bits — Each of these control bits determines if the internal pull-up device is
PTCPE[7:0]	enabled for the associated PTC pin. For port C pins that are configured as outputs, these bits have no effect and
	the internal pull devices are disabled.
	0 Internal pull-up device disabled for port C bit n.
	1 Internal pull-up device enabled for port C bit n.

NOTE

Pull-down devices only apply when using pin interrupt functions, when corresponding edge select and pin select functions are configured.

6.5.3.4 Port C Slew Rate Enable Register (PTCSE)



Figure 6-22. Slew Rate Enable for Port C Register (PTCSE)

Table 6-20. PTCSE Register Field Descriptions

Field	Description
7:0 PTCSE[7:0]	 Output Slew Rate Enable for Port C Bits — Each of these control bits determines if the output slew rate control is enabled for the associated PTC pin. For port C pins that are configured as inputs, these bits have no effect. Output slew rate control disabled for port C bit n. Output slew rate control enabled for port C bit n.

Note: Slew rate reset default values may differ between engineering samples and final production parts. Always initialize slew rate control to the desired value to ensure correct operation.



Chapter 6 Parallel Input/Output Control

6.5.3.5 Port C Drive Strength Selection Register (PTCDS)

_	7	6	5	4	3	2	1	0
R W	PTCDS7	PTCDS6	PTCDS5	PTCDS4	PTCDS3	PTCDS2	PTCDS1	PTCDS0
Reset:	0	0	0	0	0	0	0	0

Figure 6-23. Drive Strength Selection for Port C Register (PTCDS)

Table 6-21. PTCDS Register Field Descriptions

Field	Description
7:0 PTCDS[7:0]	 Output Drive Strength Selection for Port C Bits — Each of these control bits selects between low and high output drive for the associated PTC pin. For port C pins that are configured as inputs, these bits have no effect. 0 Low output drive strength selected for port C bit n. 1 High output drive strength selected for port C bit n.



Chapter 8 Multi-Purpose Clock Generator (S08MCGV1)

• LP bit is written to 0

In FLL bypassed internal mode, the MCGOUT clock is derived from the internal reference clock. The FLL clock is controlled by the internal reference clock, and the FLL clock frequency locks to 1024 times the reference frequency, as selected by the RDIV bits. The MCGLCLK is derived from the FLL and the PLL is disabled in a low power state.

8.4.1.4 FLL Bypassed External (FBE)

In FLL bypassed external (FBE) mode, the MCGOUT clock is derived from the external reference clock and the FLL is operational but its output clock is not used. This mode is useful to allow the FLL to acquire its target frequency while the MCGOUT clock is driven from the external reference clock.

The FLL bypassed external mode is entered when all the following conditions occur:

- CLKS bits are written to 10
- IREFS bit is written to 0
- PLLS bit is written to 0
- RDIV bits are written to divide reference clock to be within the range of 31.25 kHz to 39.0625 kHz
- LP bit is written to 0

In FLL bypassed external mode, the MCGOUT clock is derived from the external reference clock. The external reference clock which is enabled can be an external crystal/resonator or it can be another external clock source. The FLL clock is controlled by the external reference clock, and the FLL clock frequency locks to 1024 times the reference frequency, as selected by the RDIV bits. The MCGLCLK is derived from the FLL and the PLL is disabled in a low power state.

NOTE

It is possible to briefly operate in FBE mode with an FLL reference clock frequency that is greater than the specified maximum frequency. This can be necessary in applications that operate in PEE mode using an external crystal with a frequency above 5 MHz. Please see 8.5.2.4, "Example # 4: Moving from FEI to PEE Mode: External Crystal = 8 MHz, Bus Frequency = 8 MHz for a detailed example.

8.4.1.5 PLL Engaged External (PEE)

The PLL engaged external (PEE) mode is entered when all the following conditions occur:

- CLKS bits are written to 00
- IREFS bit is written to 0
- PLLS bit is written to 1
- RDIV bits are written to divide reference clock to be within the range of 1 MHz to 2 MHz

In PLL engaged external mode, the MCGOUT clock is derived from the PLL clock which is controlled by the external reference clock. The external reference clock which is enabled can be an external crystal/resonator or it can be another external clock source The PLL clock frequency locks to a



8.4.3 Bus Frequency Divider

The BDIV bits can be changed at anytime and the actual switch to the new frequency will occur immediately.

8.4.4 Low Power Bit Usage

The low power bit (LP) is provided to allow the FLL or PLL to be disabled and thus conserve power when these systems are not being used. However, in some applications it may be desirable to enable the FLL or PLL and allow it to lock for maximum accuracy before switching to an engaged mode. Do this by writing the LP bit to 0.

8.4.5 Internal Reference Clock

When IRCLKEN is set the internal reference clock signal will be presented as MCGIRCLK, which can be used as an additional clock source. The MCGIRCLK frequency can be re-targeted by trimming the period of the internal reference clock. This can be done by writing a new value to the TRIM bits in the MCGTRM register. Writing a larger value will decrease the MCGIRCLK frequency, and writing a smaller value to the MCGTRM register will increase the MCGIRCLK frequency. The TRIM bits will effect the MCGOUT frequency if the MCG is in FLL engaged internal (FEI), FLL bypassed internal (FBI), or bypassed low power internal (BLPI) mode. The TRIM and FTRIM value is initialized by POR but is not affected by other resets.

Until MCGIRCLK is trimmed, programming low reference divider (RDIV) factors may result in MCGOUT frequencies that exceed the maximum chip-level frequency and violate the chip-level clock timing specifications (see the Device Overview chapter).

If IREFSTEN and IRCLKEN bits are both set, the internal reference clock will keep running during stop mode in order to provide a fast recovery upon exiting stop.

8.4.6 External Reference Clock

The MCG module can support an external reference clock with frequencies between 31.25 kHz to 5 MHz in FEE and FBE modes, 1 MHz to 16 MHz in PEE and PBE modes, and 0 to 40 MHz in BLPE mode. When ERCLKEN is set, the external reference clock signal will be presented as MCGERCLK, which can be used as an additional clock source. When IREFS = 1, the external reference clock will not be used by the FLL or PLL and will only be used as MCGERCLK. In these modes, the frequency can be equal to the maximum frequency the chip-level timing specifications will support (see the Device Overview chapter).

If EREFSTEN and ERCLKEN bits are both set or the MCG is in FEE, FBE, PEE, PBE or BLPE mode, the external reference clock will keep running during stop mode in order to provide a fast recovery upon exiting stop.

If CME bit is written to 1, the clock monitor is enabled. If the external reference falls below a certain frequency (f_{loc_high} or f_{loc_low} depending on the RANGE bit in the MCGC2), the MCU will reset. The LOC bit in the System Reset Status (SRS) register will be set to indicate the error.



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The table below shows MCGOUT frequency calculations using RDIV, BDIV, and VDIV settings for each clock mode. The bus frequency is equal to MCGOUT divided by 2.

Clock Mode	^f мсgouт ¹	Note
FEI (FLL engaged internal)	(f _{int} * 1024) / B	Typical f _{MCGOUT} = 16 MHz immediately after reset. RDIV bits set to %000.
FEE (FLL engaged external)	(f _{ext} / R *1024) / B	f _{ext} / R must be in the range of 31.25 kHz to 39.0625 kHz
FBE (FLL bypassed external)	f _{ext} / B	f _{ext} / R must be in the range of 31.25 kHz to 39.0625 kHz
FBI (FLL bypassed internal)	f _{int} / B	Typical f _{int} = 32 kHz
PEE (PLL engaged external)	[(f _{ext} / R) * M] / B	f _{ext} / R must be in the range of 1 MHz to 2 MHz
PBE (PLL bypassed external)	f _{ext} / B	f _{ext} / R must be in the range of 1 MHz to 2 MHz
BLPI (Bypassed low power internal)	f _{int} / B	
BLPE (Bypassed low power external)	f _{ext} / B	

¹ R is the reference divider selected by the RDIV bits, B is the bus frequency divider selected by the BDIV bits, and M is the multiplier selected by the VDIV bits.

This section will include 3 mode switching examples using a 4 MHz external crystal. If using an external clock source less than 1 MHz, the MCG should not be configured for any of the PLL modes (PEE and PBE).

8.5.2.1 Example # 1: Moving from FEI to PEE Mode: External Crystal = 4 MHz, Bus Frequency = 8 MHz

In this example, the MCG will move through the proper operational modes from FEI to PEE mode until the 4 MHz crystal reference frequency is set to achieve a bus frequency of 8 MHz. Because the MCG is in FEI mode out of reset, this example also shows how to initialize the MCG for PEE mode out of reset. First, the code sequence will be described. Then a flowchart will be included which illustrates the sequence.

- 1. First, FEI must transition to FBE mode:
 - a) MCGC2 = 0x36 (%00110110)
 - BDIV (bits 7 and 6) set to %00, or divide-by-1
 - RANGE (bit 5) set to 1 because the frequency of 4 MHz is within the high frequency range
 - HGO (bit 4) set to 1 to configure external oscillator for high gain operation
 - EREFS (bit 2) set to 1, because a crystal is being used
 - ERCLKEN (bit 1) set to 1 to ensure the external reference clock is active
 - b) Loop until OSCINIT (bit 1) in MCGSC is 1, indicating the crystal selected by the EREFS bit has been initialized.



Chapter 8 Multi-Purpose Clock Generator (S08MCGV1)



Figure 8-9. Flowchart of FEI to PEE Mode Transition using a 4 MHz crystal

MC9S08DN60 Series Data Sheet, Rev 3



Chapter 10 Analog-to-Digital Converter (S08ADC12V1)





MC9S08DN60 Series Data Sheet, Rev 3



configured for low power operation, long sample time, continuous conversion, and automatic compare of the conversion result to a software determined compare value.

10.4.4.1 Initiating Conversions

A conversion is initiated:

- Following a write to ADCSC1 (with ADCH bits not all 1s) if software triggered operation is selected.
- Following a hardware trigger (ADHWT) event if hardware triggered operation is selected.
- Following the transfer of the result to the data registers when continuous conversion is enabled.

If continuous conversions are enabled, a new conversion is automatically initiated after the completion of the current conversion. In software triggered operation, continuous conversions begin after ADCSC1 is written and continue until aborted. In hardware triggered operation, continuous conversions begin after a hardware trigger event and continue until aborted.

10.4.4.2 Completing Conversions

A conversion is completed when the result of the conversion is transferred into the data result registers, ADCRH and ADCRL. This is indicated by the setting of COCO. An interrupt is generated if AIEN is high at the time that COCO is set.

A blocking mechanism prevents a new result from overwriting previous data in ADCRH and ADCRL if the previous data is in the process of being read while in 12-bit or 10-bit MODE (the ADCRH register has been read but the ADCRL register has not). When blocking is active, the data transfer is blocked, COCO is not set, and the new result is lost. In the case of single conversions with the compare function enabled and the compare condition false, blocking has no effect and ADC operation is terminated. In all other cases of operation, when a data transfer is blocked, another conversion is initiated regardless of the state of ADCO (single or continuous conversions enabled).

If single conversions are enabled, the blocking mechanism could result in several discarded conversions and excess power consumption. To avoid this issue, the data registers must not be read after initiating a single conversion until the conversion completes.

10.4.4.3 Aborting Conversions

Any conversion in progress is aborted when:

- A write to ADCSC1 occurs (the current conversion will be aborted and a new conversion will be initiated, if ADCH are not all 1s).
- A write to ADCSC2, ADCCFG, ADCCVH, or ADCCVL occurs. This indicates a mode of operation change has occurred and the current conversion is therefore invalid.
- The MCU is reset.
- The MCU enters stop mode with ADACK not enabled.



Table 12-3. SPIC2 Register Field Descriptions

Field	Description				
4 MODFEN	 Master Mode-Fault Function Enable — When the SPI is configured for slave mode, this bit has no meaning or effect. (The SS pin is the slave select input.) In master mode, this bit determines how the SS pin is used (refer to Table 12-2 for more details). Mode fault function disabled, master SS pin reverts to general-purpose I/O not controlled by SPI Mode fault function enabled, master SS pin acts as the mode fault input or the slave select output 				
3 BIDIROE	Bidirectional Mode Output Enable — When bidirectional mode is enabled by SPI pin control 0 (SPC0) = 1, BIDIROE determines whether the SPI data output driver is enabled to the single bidirectional SPI I/O pin. Depending on whether the SPI is configured as a master or a slave, it uses either the MOSI (MOMI) or MISO (SISO) pin, respectively, as the single SPI data I/O pin. When SPC0 = 0, BIDIROE has no meaning or effect. 0 Output driver disabled so SPI data I/O pin acts as an input 1 SPI I/O pin enabled as an output				
1 SPISWAI	SPI Stop in Wait Mode 0 SPI clocks continue to operate in wait mode 1 SPI clocks stop when the MCU enters wait mode				
0 SPC0	 SPI Pin Control 0 — The SPC0 bit chooses single-wire bidirectional mode. If MSTR = 0 (slave mode), the SPI uses the MISO (SISO) pin for bidirectional SPI data transfers. If MSTR = 1 (master mode), the SPI uses the MOSI (MOMI) pin for bidirectional SPI data transfers. When SPC0 = 1, BIDIROE is used to enable or disable the output driver for the single bidirectional SPI I/O pin. O SPI uses separate pins for data input and data output 1 SPI configured for single-wire bidirectional operation 				

12.4.3 SPI Baud Rate Register (SPIBR)

This register is used to set the prescaler and bit rate divisor for an SPI master. This register may be read or written at any time.



= Unimplemented or Reserved

Figure 12-7. SPI Baud Rate Register (SPIBR)

Table 12-4. SPIBR Register Field Descriptions

Field	Description
6:4 SPPR[2:0]	SPI Baud Rate Prescale Divisor — This 3-bit field selects one of eight divisors for the SPI baud rate prescaler as shown in Table 12-5. The input to this prescaler is the bus rate clock (BUSCLK). The output of this prescaler drives the input of the SPI baud rate divider (see Figure 12-4).
2:0 SPR[2:0]	SPI Baud Rate Divisor — This 3-bit field selects one of eight divisors for the SPI baud rate divider as shown in Table 12-6. The input to this divider comes from the SPI baud rate prescaler (see Figure 12-4). The output of this divider is the SPI bit rate clock for master mode.







In input capture mode, reading either byte (TPMxCnVH or TPMxCnVL) latches the contents of both bytes into a buffer where they remain latched until the other half is read. This latching mechanism also resets (becomes unlatched) when the TPMxCnSC register is written (whether BDM mode is active or not). Any write to the channel registers will be ignored during the input capture mode.

When BDM is active, the coherency mechanism is frozen (unless reset by writing to TPMxCnSC register) such that the buffer latches remain in the state they were in when the BDM became active, even if one or both halves of the channel register are read while BDM is active. This assures that if the user was in the middle of reading a 16-bit register when BDM became active, it will read the appropriate value from the other half of the 16-bit value after returning to normal execution. The value read from the TPMxCnVH and TPMxCnVL registers in BDM mode is the value of these registers and not the value of their read buffer.

In output compare or PWM modes, writing to either byte (TPMxCnVH or TPMxCnVL) latches the value into a buffer. After both bytes are written, they are transferred as a coherent 16-bit value into the timer-channel registers according to the value of CLKSB:CLKSA bits and the selected mode, so:

- If (CLKSB:CLKSA = 0:0), then the registers are updated when the second byte is written.
- If (CLKSB:CLKSA not = 0:0 and in output compare mode) then the registers are updated after the second byte is written and on the next change of the TPM counter (end of the prescaler counting).
- If (CLKSB:CLKSA not = 0:0 and in EPWM or CPWM modes), then the registers are updated after the both bytes were written, and the TPM counter changes from (TPMxMODH:TPMxMODL 1) to (TPMxMODH:TPMxMODL). If the TPM counter is a free-running counter then the update is made when the TPM counter changes from 0xFFFE to 0xFFFF.

The latching mechanism may be manually reset by writing to the TPMxCnSC register (whether BDM mode is active or not). This latching mechanism allows coherent 16-bit writes in either big-endian or little-endian order which is friendly to various compiler implementations.

When BDM is active, the coherency mechanism is frozen such that the buffer latches remain in the state they were in when the BDM became active even if one or both halves of the channel register are written while BDM is active. Any write to the channel registers bypasses the buffer latches and directly write to the channel register while BDM is active. The values written to the channel register while BDM is active



TPM counter changes from (TPMxMODH:L - 1) to (TPMxMODH:L). If the TPM counter is a free-running counter, then this update is made when the TPM counter changes from \$FFFE to \$FFFF. Instead, the TPM v2 makes this update after that the both bytes were written and when the TPM counter changes from TPMxMODH:L to \$0000.

— Center-Aligned PWM (Section 15.4.2.4, "Center-Aligned PWM Mode)

In this mode and if (CLKSB:CLKSA not = 00), the TPM v3 updates the TPMxCnVH:L registers with the value of their write buffer after that the both bytes were written and when the TPM counter changes from (TPMxMODH:L - 1) to (TPMxMODH:L). If the TPM counter is a free-running counter, then this update is made when the TPM counter changes from \$FFFE to \$FFFF. Instead, the TPM v2 makes this update after that the both bytes were written and when the TPM counter changes from TPMxMODH:L to (TPMxMODH:L - 1).

- 5. Center-Aligned PWM (Section 15.4.2.4, "Center-Aligned PWM Mode)
 - TPMxCnVH:L = TPMxMODH:L [SE110-TPM case 1]
 In this case, the TPM v3 produces 100% duty cycle. Instead, the TPM v2 produces 0% duty cycle.
 - TPMxCnVH:L = (TPMxMODH:L 1) [SE110-TPM case 2]

In this case, the TPM v3 produces almost 100% duty cycle. Instead, the TPM v2 produces 0% duty cycle.

- TPMxCnVH:L is changed from 0x0000 to a non-zero value [SE110-TPM case 3 and 5] In this case, the TPM v3 waits for the start of a new PWM period to begin using the new duty cycle setting. Instead, the TPM v2 changes the channel output at the middle of the current PWM period (when the count reaches 0x0000).
- TPMxCnVH:L is changed from a non-zero value to 0x0000 [SE110-TPM case 4]
 In this case, the TPM v3 finishes the current PWM period using the old duty cycle setting.
 Instead, the TPM v2 finishes the current PWM period using the new duty cycle setting.
- 6. Write to TPMxMODH:L registers in BDM mode (Section 15.3.3, "TPM Counter Modulo Registers (TPMxMODH:TPMxMODL))

In the TPM v3 a write to TPMxSC register in BDM mode clears the write coherency mechanism of TPMxMODH:L registers. Instead, in the TPM v2 this coherency mechanism is not cleared when there is a write to TPMxSC register.

7. Update of EPWM signal when CLKSB:CLKSA = 00

In the TPM v3 if CLKSB:CLKSA = 00, then the EPWM signal in the channel output is not update (it is frozen while CLKSB:CLKSA = 00). Instead, in the TPM v2 the EPWM signal is updated at the next rising edge of bus clock after a write to TPMxCnSC register.

The Figure 0-1 and Figure 0-2 show when the EPWM signals generated by TPM v2 and TPM v3 after the reset (CLKSB:CLKSA = 00) and if there is a write to TPMxCnSC register.



Chapter 15 Timer/PWM Module (S08TPMV3)



Chapter 16 Development Support

16.2.3 BDC Commands

BDC commands are sent serially from a host computer to the BKGD pin of the target HCS08 MCU. All commands and data are sent MSB-first using a custom BDC communications protocol. Active background mode commands require that the target MCU is currently in the active background mode while non-intrusive commands may be issued at any time whether the target MCU is in active background mode or running a user application program.

Table 16-1 shows all HCS08 BDC commands, a shorthand description of their coding structure, and the meaning of each command.

Coding Structure Nomenclature

This nomenclature is used in Table 16-1 to describe the coding structure of the BDC commands.

Commands begin with an 8-bit hexadecimal command code in the host-to-target direction (most significant bit first)

- / = separates parts of the command
- d = delay 16 target BDC clock cycles
- AAAA = a 16-bit address in the host-to-target direction
 - RD = 8 bits of read data in the target-to-host direction
 - WD = 8 bits of write data in the host-to-target direction
- RD16 = 16 bits of read data in the target-to-host direction
- WD16 = 16 bits of write data in the host-to-target direction
 - SS = the contents of BDCSCR in the target-to-host direction (STATUS)
 - CC = 8 bits of write data for BDCSCR in the host-to-target direction (CONTROL)
- RBKP = 16 bits of read data in the target-to-host direction (from BDCBKPT breakpoint register)
- WBKP = 16 bits of write data in the host-to-target direction (for BDCBKPT breakpoint register)



Appendix A Electrical Characteristics

where K is a constant pertaining to the particular part. K can be determined from equation 3 by measuring P_D (at equilibrium) for a known T_A . Using this value of K, the values of P_D and T_J can be obtained by solving equations 1 and 2 iteratively for any value of T_A .

A.5 ESD Protection and Latch-Up Immunity

Although damage from electrostatic discharge (ESD) is much less common on these devices than on early CMOS circuits, normal handling precautions should be used to avoid exposure to static discharge. Qualification tests are performed to ensure that these devices can withstand exposure to reasonable levels of static without suffering any permanent damage.

All ESD testing is in conformity with AEC-Q100 Stress Test Qualification for Automotive Grade Integrated Circuits. During the device qualification ESD stresses were performed for the Human Body Model (HBM) and the Charge Device Model (CDM).

A device is defined as a failure if after exposure to ESD pulses the device no longer meets the device specification. Complete DC parametric and functional testing is performed per the applicable device specification at room temperature followed by hot temperature, unless specified otherwise in the device specification.

Model	Description	Symbol	Value	Unit
	Series Resistance	R1	1500	Ω
Human Body	Storage Capacitance	С	100	pF
	Number of Pulse per pin	-	3	
	Minimum input voltage limit		-2.5	V
Laten-up	Maximum input voltage limit		7.5	V

Table A-4. ESD and Latch-up Test Conditions

Table A-5. ESD and Latch-Up Protection Characteristics

Num	Rating	Symbol	Min	Мах	Unit
1	Human Body Model (HBM)	V _{HBM}	+/- 2000	-	V
2	Charge Device Model (CDM)	V _{CDM}	+/- 500	-	V
3	Latch-up Current at T _A = 125°C	I _{LAT}	+/- 100	-	mA



CPWMS	MSnB:MSnA	ELSnB:ELSnA	Mode	Configuration	
Х	XX	00	Pin not used for TPM channel; use as an external clock for the TPM or revert to general-purpose I/O		
0	00	01	Input capture Capture on rising edge only		
		10		Capture on falling edge only	
		11		Capture on rising or falling edge	
	01	00	Output	Software compare only	
		01	compare	Toggle output on compare	
		10		Clear output on compare	
		11		Set output on compare	
	1X	10	Edge-aligned	High-true pulses (clear output on compare)	
		X1	PVVM	Low-true pulses (set output on compare)	
1	XX	10	Center-aligned	High-true pulses (clear output on compare-up)	
		X1	PVVM	Low-true pulses (set output on compare-up)	

Table	B-5.	Mode.	Edge.	and Lev	el Selection
Tubic	D U.	mouc,	Lugo,		00000000

If the associated port pin is not stable for at least two bus clock cycles before changing to input capture mode, it is possible to get an unexpected indication of an edge trigger. Typically, a program would clear status flags after changing channel configuration bits and before enabling channel interrupts or using the status flags to avoid any unexpected behavior.

B.2.5 Timer Channel Value Registers (TPMxCnVH:TPMxCnVL)

These read/write registers contain the captured TPM counter value of the input capture function or the output compare value for the output compare or PWM functions. The channel value registers are cleared by reset.



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